

Electronic Supplementary Information (ESI)

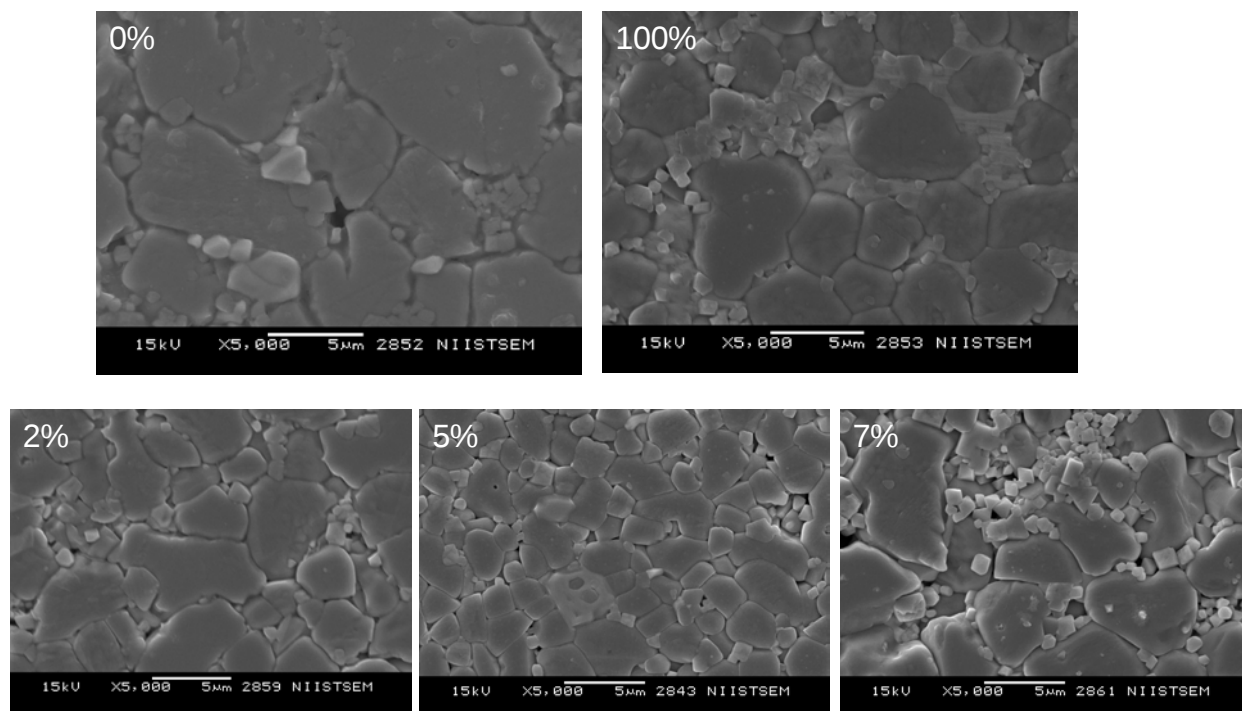


Fig. S1 Low magnification (5,000 X) SEM images of the nanofiller added varistors.

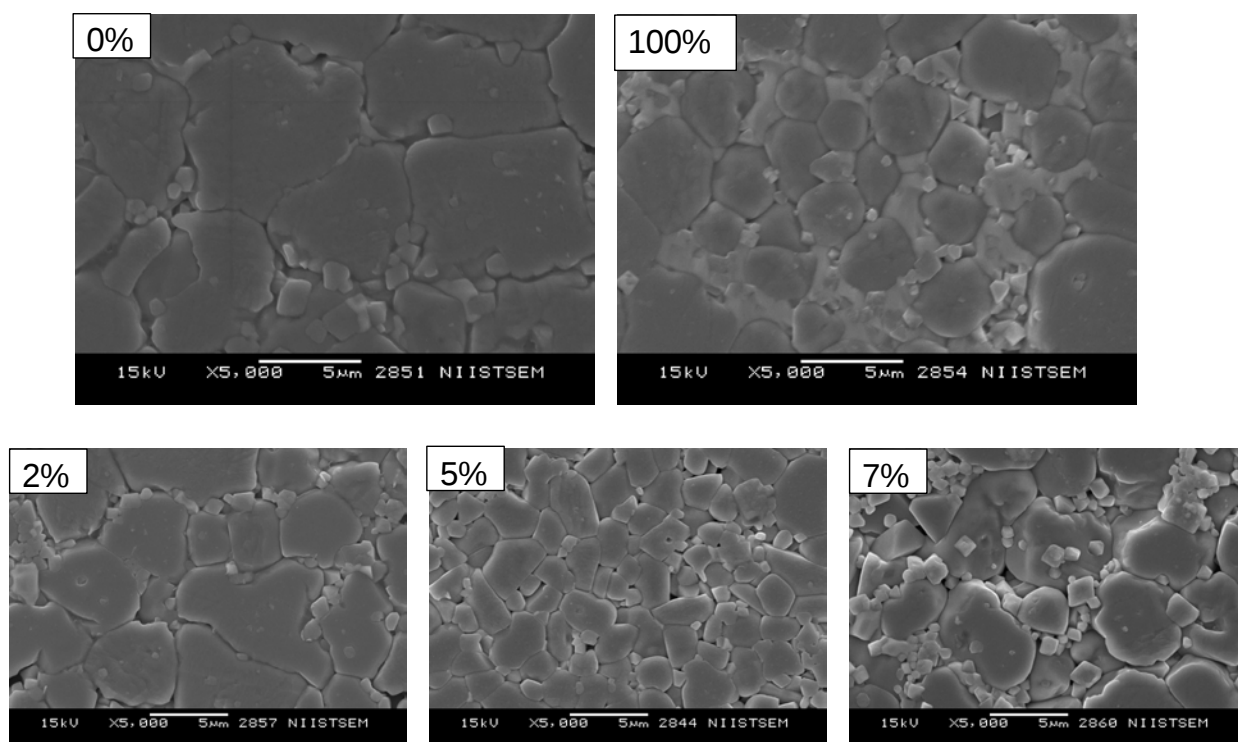


Fig. S2 SEM images of the nanofiller added varistors (images taken from another area).

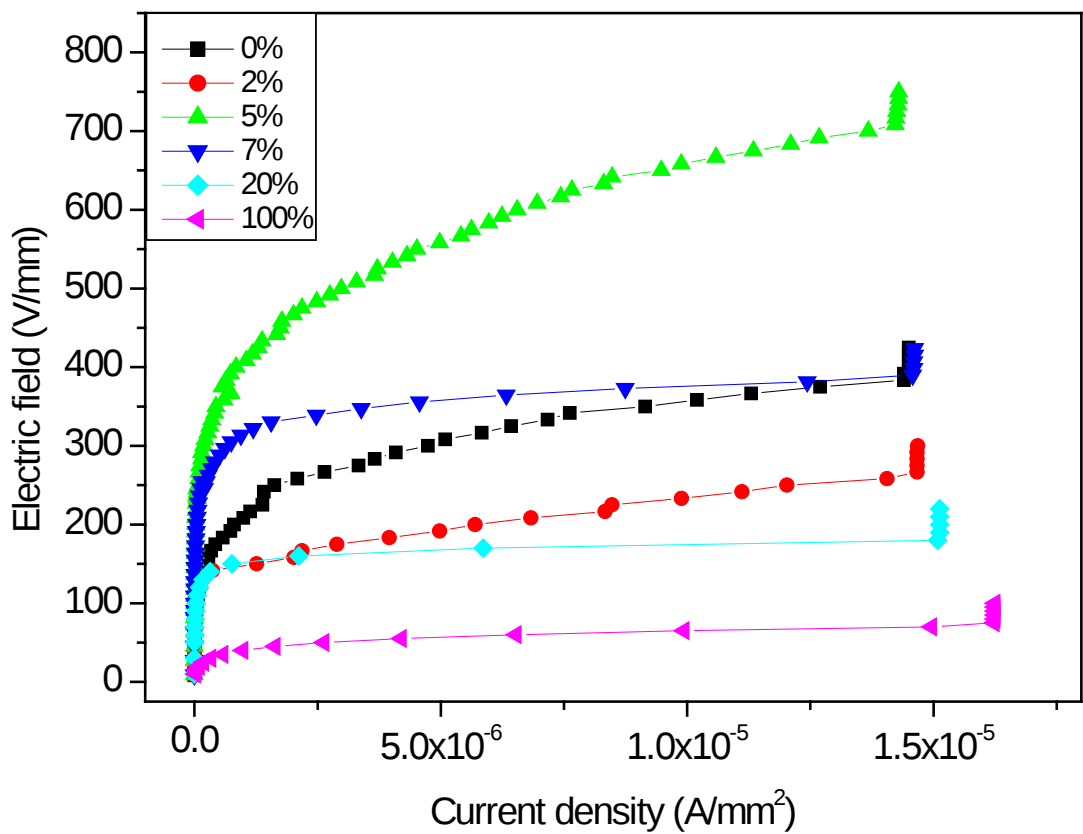


Fig. S3 I/V analysis of microwave sintered varistor samples at 1100 °C.